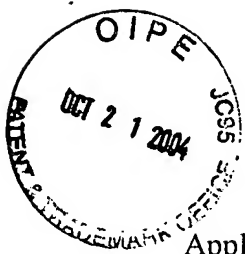


IFW



Attorney's Docket No.: 09712-331001 / Z-430

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Henry A. Hill
Serial No. : 10/630,361
Filed : July 29, 2003
Title : COMPENSATION FOR ERRORS IN OFF-AXIS INTERFEROMETRIC MEASUREMENTS

Art Unit : 2877
Examiner : Unknown

Mail Stop Amendment
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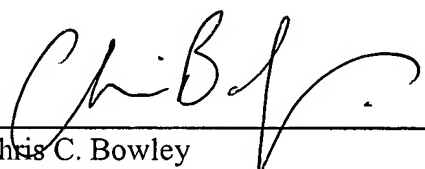
INFORMATION DISCLOSURE STATEMENT

Copies of the references listed on the attached form PTO-1449 are not enclosed pursuant to 37 CFR 1.98(a)(2)(iii).

This statement is being filed within three months of the filing date of the application or before the receipt of a first Office Action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 10/18/2004

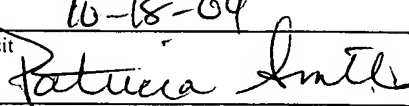

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I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-331001	Application No. 10/630,361
	Applicant Henry A. Hill		
	Filing Date July 29, 2003	Group Art Unit 2877	

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,790,253	08/04/98	Kamiya Saburo			
	AB	6,137,574	10/24/00	Hill			
	AC	5,151,749	09/29/92	Kamiya Saburo et al.			
	AD	6,181,420	01/30/01	Zanoni			

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AE							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
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Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	